

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20221031002.1

Qualification of new Fab site (RFAB) using qualified Process Technology, Die Revision, Datasheet update and additional Assembly site option for select devices Change Notification / Sample Request

Date: November 01, 2022

To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments (TI). The details of this change are on the following pages, and are in alignment with our standard product change notification (PCN) <u>process</u>.

TI requires acknowledgement of receipt of this notification within 30 days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within 30 days of this notification, given that samples are not built ahead of the change.

The Proposed First Ship date in this PCN letter is the earliest possible date that customers could receive the changed material. It is our commitment that the changed device will not ship before that date. If samples are requested within the 30 day sample request window, customers will still have 30-days to complete their evaluation regardless of the proposed 1st ship date.

This particular PCN is related to TI's multiyear transition plan for our two remaining factories with 150-millimeter production (DFAB in Dallas, Texas, and SFAB in Sherman, Texas). DFAB will remain open, but will focus on 200-mm production, with a smaller set of technologies. SFAB will close no earlier than 2024 and no later than 2025. As referenced in the "reason for change" below, these changes are part of our multiyear plan to transition these products to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (PCN www admin team@list.ti.com). For sample requests or sample related questions, contact your local Field Sales Representative. As always, we thank you for your continued business.

PCN Team SC Business Services

20221031002.1 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
MAX3243EIDBR	null
MAX3243CPWRG4	null
MAX3243ECPWR	null
MAX3243EIPWR	null
MAX3243IPWR	null
TRS3243EIPWR	null
MAX3243CDBR	null
MAX3243CPWR	null
TRS3243ECDBR	null
MAX3243IDBR	null
TRS3243ECPWR	null
MAX3243EIRHBR	null
SN75C3243PWR	null
SN75C3243DBR	null
MAX3243ECDBR	null
TRSF3243IPWR	null

Technical details of this Product Change follow on the next page(s).

PCN Number: 2022		0221031002.1		PCN Date:		e:	November 01, 2022			
Title	e:				b site (RFAB) using o additional Assembly					
Cus	tomer	Contact:		PCN N	<u>lanager</u>	Dept:			Qua	ality Services
Proposed 1 st Ship Date:		Jan 3	n 31, 2023 Sample re accepted		· INOV 30 7077本		30, 2022*			
*Sa	mple ı	equests rece	ived	l afte	r November 30, 2	022 will no	t be	supp	orte	ed.
Cha	nge Ty	/pe:								
\boxtimes	Assen	nbly Site			Assembly Process		\boxtimes	Asse	mbly	/ Materials
\boxtimes	Desigi	า			Electrical Specifica	tion		Mecl	hanio	al Specification
	Test S	Site			Packing/Shipping/Labeling			Test	Prod	cess
☐ Wafer Bump Site			Wafer Bump Material			Wafe	er Bu	ımp Process		
		X	Wafer Fab Material	S	\boxtimes	Wafe	er Fa	b Process		
			☐ Part number change							
	PCN Details									

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (RFAB, LBC7) and additional Assembly site (CDAT) for selected devices listed below in the product affected section.

Current Fab Site			A	dditional Fab S	ite
Current Fab Site	Process	Wafer Additional Diameter Fab Site		Process	Wafer Diameter
DL-LIN	LBC3S	150 mm	RFAB	LBC7	300 mm
DL-LIN	LBC3S	200 mm	READ	LDC/	300 11111

The die was also changed as a result of the process change.

Construction differences are as follows:

Group 2 Devices (RFAB/Process migration & CDAT as an alternate Assembly site):

	MLA	CDAT
Mold Compound	4208625	4222198
Mount Compound	4205846	4207123

The datasheets will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The links to the revised datasheets are available in the table below.



MAX3243E

SLLS657E - APRIL 2005 - REVISED OCTOBER 2022

Changes from Revision D	(September 2011)	to Revision E	(October 2022)
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Page

- Deleted Ordering Information table......1



Cha	inges from Revision C (September 2011) to Rev	vision D (October 2022)	Page
	Deleted the Ordering Information table		
•	Added Device Information table, Pin Configuration	and Functions section, Feature Description s	ection,
	Device Functional Modes, Application and Impleme	entation section, Device and Documentation	Support
	section, and Mechanical, Packaging, and Orderable	e Information section	1
•	Changed the front page image from Block Diagram	to Simplified Circuit	1
	Added the ESD Ratings - IEC Specifications table		
•	Changed the I _{CC} Supply current auto-powerdown d	disabled MAX value from 1 mA to 1.2 mA in the	ne <i>Electrical</i>
	Characteristics		
_			
Į.	Texas Instruments	SLLS350P – APRIL 1999 – REVISI	MAX3243 ED OCTOBER 2022
Cha	nges from Revision O (January 2015) to Revisi		
	Changed the Thermal Information table		
	Changed the MAX value of I _{CC} Supply current auto		
	Characteristics—Auto Power Down		
4	Texas Instruments	SN65C3 : SLLS353I – JUNE 1999 – REVI	243, SN75C3243
_			
Ch	anges from Revision H (September 2008) to Rev	rision I (October 2022)	Page
•	Packaging, and Orderable Information sections Changed the I _{CC} Supply current auto-powerdown di Characteristics	lisabled MAX value from 1 mA to 1.2 mA in th	e <i>Electrical</i>
Įį.	Texas Instruments	SLLS862B – AUGUST 2007 – REVIS	TRSF3243 SED OCTOBER 2022
Ch:	nges from Revision A (September 2008) to Rev		Page
	Deleted the Ordering Information table	· · · · · · · · · · · · · · · · · · ·	
	Changed the Package Information table		
• ′	Added the Simplified SchematicAdded the Pin Configuration and Functions		
•	Added the Thermal Information table	lia a la la di NAN Viva liva fira ma di ma Aita di O ma Aita di	4
	Changed the I _{CC} Supply current auto-powerdown d		
	Characteristics		
•	Added the Detailed Description section		12
4	Texas Instruments		
— Cha		SLLS806C = JUNE 2007 = REVIS	TRS3243
OHIO	nges from Revision B (June 2015) to Revision (SLLS806C – JUNE 2007 – REVIS C (October 2022)	SED OCTOBER 2022
• (nges from Revision B (June 2015) to Revision (C (October 2022)	Page
• (changed the <i>Thermal Information</i> table	C (October 2022)	Page5
(nges from Revision B (June 2015) to Revision Changed the Thermal Information table	C (October 2022) -powerdown disabled from 1 mA to 1.2 mA in	Page 5 Dectrical

Product Folder	Current Datasheet Number	New Datasheet Number	Link to full datasheet
MAX3243E	SLLS657D	SLLS657E	http://www.ti.com/product/MAX3243E
TRS3243E	SLLS789C	SLLS789D	http://www.ti.com/product/TRS3243E
MAX3243	SLLS3500	SLLS350P	http://www.ti.com/product/MAX3243
SN75C3243	SLLS353H	SLLS353I	http://www.ti.com/product/SN75C3243
TRSF3243	SLLS862A	SLLS862B	http://www.ti.com/product/TRSF3243
TRS3243	SLLS806B	SLLS806C	http://www.ti.com/product/TRS3243

Tube, Temp, ESD and G4 variants of the devices are included in EOL notice PDN# 20221031003.3

Qual details are provided in the Qual Data Section.

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-milimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
☑ No Change		☑ No Change	☑ No Change

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DL-LIN	DLN	USA	Dallas
RFAB	RFB	USA	Richardson

Die Rev:

Current New

Die Rev [2P]	Die Rev [2P]
L, H, C	A

Assembly Site Information:

CDAT	CDA	CHN	Chengdu
TI Malaysia	MLA	MYS	Kuala Lumpur
Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS

MADE IN: Malaysia 2DC: 2Q:

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

OPT: ITEM:

(L)T0:1750 LBL:



(1P) SN74LS07NSR (D) 0336 31T)LOT: 3959047MLA 4W) TKY(1T) 7523483S12

(2P) REV: (V) 003331/ (Z1L) CCO:USA (23L) ACO: MYS (20L) CSO: SHE (22L) ASO: MLA

Product Affected:

Group 1 Devices (RFAB/Process migration only):

MAX3243CDBR	MAX3243ECPWRG4	MAX3243IPW RE4	TRS3243ECDBR
MAX3243CDBRE4	MAX3243EIDBR	SN65C3243DBR	TRS3243ECPWR
MAX3243CPWR	MAX3243EIPWR	SN65C3243PWR	TRS3243EIDBR
MAX3243CPWRG4	MAX3243EIPW RE4	SN75C3243DBR	TRS3243EIPWR
MAX3243ECDBR	MAX3243IDBR	SN75C3243PWR	TRSF3243IPWR
MAX3243ECPWR	MAX3243IPWR	TRS3243CDBR	

Group 2 Devices (RFAB/Process migration & CDAT as an alternate Assembly site):

MAX3243ECRHBR	MAX3243EIRHBRG4	TRS3243EIRHBR	TRS3243EIRHBRG4
MAX3243EIRHBR	TRS3243ECRHBR		

For alternate parts with similar or improved performance, please visit the product page on TI.com

Qualification Report Approve Date 27-September-2022

Qualification Results

Туре	#	Test Name	Condition	Duration	Qual Device: TRS3243EIDBR	QBS Reference: IPS53605DSQR	QBS Reference: IPS51217DSCR	QBS Reference: IPS51218DSCR	QBS Reference: TLC320AD77CDBR	QBS Reference: IRS3243EIRHBR	QBS Reference: IPD3S714QDBQRQ1
HAST	A2	Biased HAST	110C	264 Hours	-	3/231/0	-	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-	-	-
UHAST	А3	Autoclave	121C/15psig	96 Hours	1/77/0	-	3/231/0	-	3/231/0	-	-
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	3/231/0
UHAST	А3	Unbiased HAST	110C	264 Hours	-	3/231/0	-	-	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	3/231/0	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	3/231/0	3/231/0	-	3/231/0	-	-
HTSL	A 6	High Temperature Storage Life	170C	420 Hours	-	2/154/0	3/231/0	-	3/231/0	-	-
HTOL	B1	CL (FF)	125C	1000 Hours	-	1/45/0	-	-	-	-	-
HTOL	B1	CL (FS)	125C	1000 Hours	-	1/32/0	-	-	-	-	-
HTOL	B1	CL (SF)	125C	1000 Hours	-	1/32/0	-	-	-	-	-
HTOL	B1	CL (SS)	125C	1000 Hours	-	1/45/0	-	-	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-	-	-

HTOL	B1	Life Test	135C	635 Hours	-	-	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	408 Hours	-	-	-	-	-	-	3/231/0
ELFR	B2	ELFR	125C	48 Hours	-	3/2999/0	-	-	-	-	-
ELFR	B2	Early Life Failure Rate	150C	24 Hours	-	-	-	-	-	-	3/2400/0
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	-	-	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	-	-	1/76/0	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	-	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	-	-	1/76/0	3/228/0
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	3/90/0	-	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	3/30/0
ESD	E2	ESD CDM	-	1500 Volts	-	-	3/9/0	-	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	-	-	-	-	-	-	3/9/0
ESD	E2	ESD CDM	-	250 Volts	1/3/0	3/9/0	-	-	-	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	-	3/9/0	-	-	-	1/3/0	-
ESD	E2	ESD HBM	-	2000 Volts	-	-	3/9/0	-	-	-	-
ESD	E2	ESD HBM	-	4000 Volts	-	-	-	-	-	-	3/9/0
LU	E4	Latch-Up	Per JESD78	-	-	-	3/18/0	-	-	1/3/0	-
CHAR	E5	Electrical Characterization	Min, Typ, Max Temp	-	1/30/0	3/90/0	3/60/0	1/30/0	-	1/30/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	3/90/0	3/60/0	1/30/0	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	-	-	3/90/0
FTY	E6	Final Test Yield	-	-	1/1/0	-	-	-	-	-	-
		-									

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
 The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/Ik Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
 The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/Ik Hours, and 170C/420 Hours
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Qualified Pb-Free(SMT) and Green

QBS: Qual By Similarity
 Qual Device TRS3243EIDBR is qualified at MSL1 260C

Qualification Report Approved 24-Feb-2022

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TR \$3243EIRHBR	QBS Process Reference: TPS51217DSC	QBS Process Reference: TPS51218DSC	QBS Process Reference: TPS53605DSQ	QBS Package Reference: 430F2132IRHBR	QBS Package Reference: <u>TPS2546QRTERQ1</u>
AC	Autoclave 121C	96 Hours	-	6/462/0	-	-	3/231/0	3/231/0
CDM	ESD - CDM	1500 V	1/3/0	3/9/0	-	2/6/0	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	Pass	-	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	3/2999/0	-	-
HAST	Biased HAST 130C/85%RH	96 Hours	-	3/231/0	-	-	-	3/231/0
нвм	ESD HBM	4000 V	1/3/0	-	-	-	-	-
HTOL	Life Test, 125C	1000 Hours	-	-	-	3/231/0	-	-
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	-	3/148/0
LU	Latch-up	(_per JESD78)	1/6/0	-	-	-	-	-
TC	Temperature Cycle, - 65/150C	500 Cycles	-	3/231/0	-	3/231/0	3/231/0	3/430/0
WBP	Bond Pull	Wires	1/76/0	-	-	-	3/228/0	-
WBS	Ball Bond Shear	Wires	1/76/0	-	-	-	3/228/0	-

- QBS: Qual By Similarity Qual Device TRS3243EIRHBR is qualified at LEVEL2-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

Qualification Report Approve Date 16-SEPTEMBER-2022

Qualification Results

Туре	#	Test Name	Condition	Duration	Qual Device: TRSF3243EIPWR	QBS Reference: TCA6408AQPWRQ1	QBS Reference: TPS23861PWR	QBS Reference: TPS51217DSCR	QBS Reference: TRSF3243EIRHBR
HAST	A2	Biased HAST	130C	96 Hours	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	3/231/0	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	3/231/0	1/77/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	1/45/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	1/77/0	-	-	-
HTOL	B1	Life Test	135C	635 Hours	-	-	-	3/231/0	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	-	-

PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	-	-	-	3/9/0	-
ESD	E2	ESD CDM	-	1500 Volts	-	1/3/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	1000 Volts	-	-	-	-	1/3/0
ESD	E2	ESD HBM	-	16000 Volts	-	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	3/9/0	-
ESD	E2	ESD HBM	-	4000 Volts	-	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	3/18/0	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	-	-	-	3/60/0	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	-	-	-

- QBS: Qual By Similarity
- Qual Device TRSF3243EIPWR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Qualification Report Approve Date 16-September-2022

Qualification Results

Туре	#	Test Name	Condition	Duration	Qual Device: PTRS3243EIPWR	QBS Reference: TCA6408AQPWRQ1	QBS Reference: TPS23861PWR	QBS Reference: TPS51217DSCR	QBS Reference: TRS3243EIRHBR
HAST	A2	Biased HAST	130C	96 Hours	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	1/77/0	-	3/231/0	3/231/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	-	3/231/0	3/231/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	1/45/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	1/77/0	-	-	-
HTOL	B1	Life Test	135C	635 Hours	-	-	-	3/231/0	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	-	1/76/0
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	-	1/76/0
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-

ESD	E2	ESD CDM	-	1500 Volts	-	-	-	3/9/0	-
ESD	E2	ESD CDM	-	1500 Volts	-	1/3/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	1000 Volts	-	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	3/9/0	-
ESD	E2	ESD HBM	-	4000 Volts	-	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	3/18/0	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	-	-	-	3/60/0	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	-	-	-

- QBS: Qual By Similarity
- Qual Device PTRS3243EIPWR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Qualification Report Approve Date 27-September-2022

Qualification Results

Туре	#	Test Name	Condition	Duration	Qual Device: PTRSF3243EIDBR	QBS Reference: TPS53605DSQR	QBS Reference: TPS51217DSCR	QBS Reference: TPS51218DSCR	QBS Reference: TLC320AD77CDBR	QBS Reference: TRSF3243EIRHBR	QBS Reference: TPD3S714QDBQRQ1
HAST	A2	Biased HAST	110C	264 Hours	-	3/231/0	-	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-	-	-
UHAST	АЗ	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-	3/231/0	1/77/0	-
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	3/231/0
UHAST	А3	Unbiased HAST	110C	264 Hours	-	3/231/0	-	-	-	-	-
тс	A4	Temperature Cycle	-65/150C	500 Cycles	-	3/231/0	3/231/0	-	-	1/77/0	-
тс	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	3/231/0	-	3/231/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	2/154/0	3/231/0	-	3/231/0	-	-
HTOL	B1	CL (FF)	125C	1000 Hours	-	1/45/0	-	-	-	-	-
HTOL	B1	CL (FS)	125C	1000 Hours	-	1/32/0	-	-	-	-	-
HTOL	B1	CL (SF)	125C	1000 Hours	-	1/32/0	-	-	-	-	-
HTOL	B1	CL (SS)	125C	1000 Hours	-	1/45/0	-	-	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-	-	-
HTOL	B1	Life Test	135C	635 Hours	-	-	3/231/0	-	-	-	-

HTOL	B1	Life Test	150C	408 Hours	-	-	-	-	-	-	3/231/0
ELFR	B2	ELFR	125C	48 Hours	-	3/2999/0	-	-	-	-	-
ELFR	B2	Early Life Failure Rate	150C	24 Hours	-	-	-	-	-	-	3/2400/0
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	1/76/0	-	-	-	-	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	1/76/0	-	-	-	-	-	3/228/0
PD	C4	Physical Dimensions	(per mechanical drawing)	-		3/90/0	-	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	3/30/0
ESD	E2	ESD CDM	-	1500 Volts	-	-	3/9/0	-	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	-	-	-	-	-	-	3/9/0
ESD	E2	ESD CDM	-	250 Volts	1/3/0	3/9/0	-	-	-	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	-	3/9/0	-	-	-	1/3/0	-
ESD	E2	ESD HBM	-	16000 Volts	-	-	-	-	-	1/3/0	
ESD	E2	ESD HBM		2000 Volts	-	-	3/9/0	-	-	-	
ESD	E2	ESD HBM	-	4000 Volts	-	-	-	-	-	-	3/9/0
LU	E4	Latch-Up	Per JESD78	-	-	-	3/18/0	-		1/3/0	
CHAR	E5	Electrical Characterization	Min, Typ, Max Temp	-	-	3/90/0	3/60/0	1/30/0	-	1/30/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	-	3/90/0	3/60/0	1/30/0	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device PTRSF3243EIDBR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	PCN ww admin team@list.ti.com

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